

Data sheet acquired from Harris Semiconductor SCHS034C – Revised October 2003

CMOS Presettable Up/Down Counter

Binary or BCD-Decade
High-Voltage Types (20-Volt Rating)

■ CD4029B consists of a four-stage binary or BCD-decade up/down counter with provisions for look-ahead carry in both counting modes. The inputs consist of a single CLOCK, CARRY-IN (CLOCK ENABLE), BINARY/DECADE, UP/DOWN, PRESET ENABLE, and four individual JAM signals. Q1, Q2, Q3, Q4 and a CARRY OUT signal are provided as outputs.

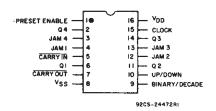
A high PRESET ENABLE signal allows information on the JAM INPUTS to preset the counter to any state asynchronously with the clock. A low on each JAM line, when the PRESET-ENABLE signal is high, resets the counter to its zero count. The counter is advanced one count at the positive transition of the clock when the CARRY-IN and PRE-SET ENABLE signals are low. Advancement is inhibited when the CARRY-IN or PRESET ENABLE signals are high. The CARRY-OUT signal is normally high and goes low when the counter reaches its maximum count in the UP mode or the minimum count in the DOWN mode provided the CARRY-IN signal is low. The CARRY-IN signal in the low state can thus be considered a CLOCK ENABLE. The CARRY-IN terminal must be connected to VSS when not in use.

Binary counting is accomplished when the BINARY/DECADE input is high; the counter counts in the decade mode when the BINARY/DECADE input is low. The counter counts up when the UP/DOWN input is high, and down when the UP/DOWN input is low. Multiple packages can be connected in either a parallel-clocking or a ripple-clocking arrangement as shown in Fig. 17.

Parallel clocking provides synchronous control and hence faster response from all counting outputs. Ripple-clocking allows for longer clock input rise and fall times.

The CD4029B-series types are supplied in 16-lead hermetic dual-in-line ceramic packages (F3A suffix), 16-lead dual-in-line plastic packages (E suffix), 16-lead small-outline packages (M, M96, MT, and NSR suffixes), and 16-lead thin shrink small-outline packages (PW and PWR suffixes).

CD4029B Terminal Diagram



CD4029B Types

Features:

- Medium-speed operation . . . 8 MHz (typ.)
 © C_L = 50 pF and V_{DD}-V_{SS} = 10 V
- Multi-package parallel clocking for synchronous high speed output response or ripple clocking for slow clock input rise and fall times
- "Preset Enable" and individual "Jam" inputs provided
- Binary or decade up/down counting
- BCD outputs in decade mode
- 100% tested for quiescent current at 20 V
- 5-V, 10-V, and 15-V parametric ratings
- Standardized, symmetrical output characteristics
- Maximum input current of 1 μA at 18 V over full package-temperature range; 100 nA at 18 V and 25°C
- Noise margin (over full package-temperature range)

1 V at V_{DD} = 5 V 2 V at V_{DD} = 10 V

2.5 V at V_{DD} = 15 V

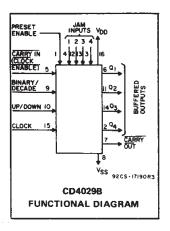
 Meets all requirements of JEDEC Tentative Standard No. 13B, "Standard Specifications

Applications:

Programmable binary and decade counting/frequency synthesizers-BCD output

for Description of 'B' Series CMOS Devices"

- Analog to digital and digital to analog conversion
- Up/Down binary counting
- Magnitude and sign generation
- Up/Down decade counting:
- Difference counting



RECOMMENDED OPERATING CONDITIONS at $T_A = 25^{\circ}$ C, Except as Noted. For maximum reliability, nominal operating conditions should be selected so that operation is always within the following ranges:

CHARACTERISTIC		V _{DD}	LIMITS		UNITS	
		(V)	Min.	Max.		
Supply-Voltage Ran Temperature Rang	nge (For T _A = Full Package- je)		3	18	٧	
Setup Time t _{SU} : Càrry-In		5 10 15	200 70 60	_ _ _		
U/D or B/D		5 10 15	340 140 100	- - -	ns	
Clock Pulse Width,	tw	5 10 15	180 90 60	- - -		
Preset Enable Pulse	Width, t _W	5 10 15	130 70 50	_ _ _		
Clock Input Freque	ncy, fCL	5 10 15	_ _ _	2 4 5.5	MHz	
Clock Rise and Fall	Time, t _r CL, t _f CL	5 10 15	- - -	15	μs	

MAXIMUM RATINGS, Absolute-Maximum Values: DC SUPPLY-VOLTAGE RANGE, (VDD)	
Voltages referenced to VSS Terminal)	0.5V to +20V
INPUT VOLTAGE RANGE, ALL INPUTS	0.5V to V _{DD} +0.5V
DC INPUT CURRENT, ANY ONE INPUT	±10mA
POWER DISSIPATION PER PACKAGE (PD):	
For T _A = -55°C to +100°C	500mW
For T _A = +100°C to +125°C	
	Dorato Emeanty at 12111177-0 to 20011177
DEVICE DISSIPATION PER OUTPUT TRANSISTOR	
DEVICE DISSIPATION PER OUTPUT TRANSISTOR FOR TA = FULL PACKAGE-TEMPERATURE RANGE (All Package)	Types)100mW
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DEVICE DISSIPATION PER OUTPUT TRANSISTOR FOR T_A = FULL PACKAGE-TEMPERATURE RANGE (All Package OPERATING-TEMPERATURE RANGE (T_A)	Types)

STATIC ELECTRICAL	CHARACTERISTICS

CHARAC- TERISTIC		DITIO		LIMITS AT INDICATED TEMPERATURES (°C)							LIMITS AT INDICATED TEMPERATURES (°C)							
	v _o	VIN	V _{DD}					+25		+25		1	S					
	(V)	(V)	(V)	-55	-40	+85	+125	Min.	Тур.	Max.								
Quiescent		0,5	5	5	5	150	150	_	0.04	5								
Device		0,10	10	10	10	300	300	_	0.04	10	μΑ							
Current,	-	0,15	15	20	20	600	600	_	0.04	20								
100		0,20	20	100	100	3000	3000	_	0.08	100								
Output Low	0.4	0,5	5	0.64	0.61	0.42	0.36	0.51	1	-								
(Sink) Current	0.5	0,10	10	1.6	1.5	1.1	0.9	1.3	2.6	_								
I _{OL} Min.	1.5	0,15	15	4.2	4	2.8	2.4	3.4	6.8	_	mA							
Output High	4.6	0,5	5	-0.64	-0.61	-0.42	-0.36	-0.51	-1	-								
(Source) Current, IOH Min.	2.5	0,5	5	-2	-1.8	-1.3	-1.15	-1.6	-3.2	_								
	9.5	0,10	10	-1.6	-1.5	-1.1	-0.9	-1.3	-2.6	_								
	13.5	0,15	15	-4.2	-4	-2.8	- 2.4	-3.4	-6.8	-								
Output Voltage:		0,5	5		0.	.05		0	0.05									
Low-Level,	-	0,10	10		0	.05		0	0.05									
VOL Max.	_	0,15	15		0.	.05	-	0	0.05	v								
Output		0,5	5		4.	95		4.95	5	_	1							
Voltage: High-Level,	_	0,10	10		9.	9.95	10	_	1									
VOH Min.	_	0,15	15		14.	.95	14.95	15	-	1								
Input Low	0.5,4.5	-	5	1.5					-	1.5	,†							
Voltage	1,9		10	3						3								
V _{IL} Max.	1.5,13.5	_	15			4		_	_	4	v							
Input High	0.5,4.5		5		3	3.5		3.5	_	_	1 '							
Voltage,	1,9	_	10			7		7	_	_								
V _{IH} Min.	1.5,13.5	1	15			11		11	-									
Input Current I _{IN} Max.	_	0,18	18	±0.1	±0.1	±1	±1	_	±10 ⁻⁵	±0.1	μА							

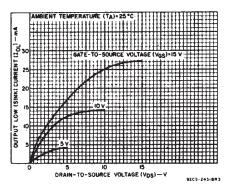


Fig. 1 — Typical output low (sink) current characteristics.

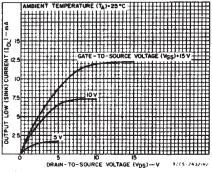


Fig. 2 — Minimum output low (sink) current characteristics.

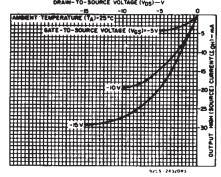


Fig. 3 - Typical output high (source) current characteristics.

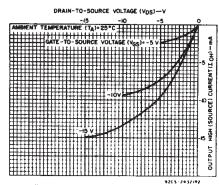


Fig. 4 — Minimum output high (source) current characteristics.

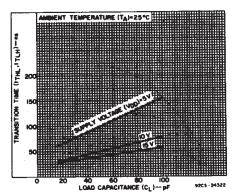


Fig. 5 — Typical transition time as a function of load capacitance.

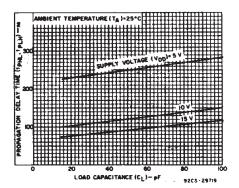


Fig. 6 — Typical propagation delay times as a function of load capacitance (Q output).

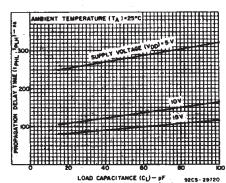


Fig. 7 — Typical propagation delay time as a function of load capacitance (carry output).

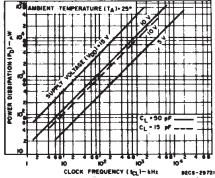
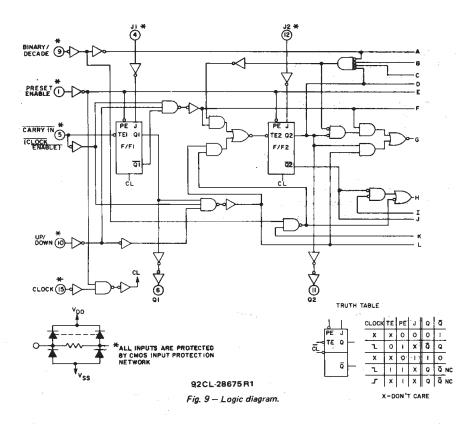


Fig. 8 – Typical power dissipation as a function of frequency.



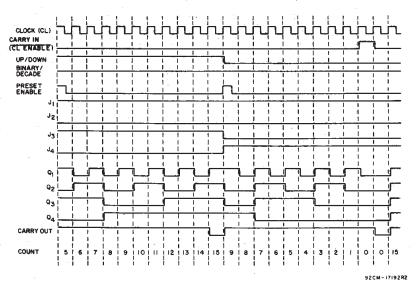


Fig. 10 - Timing diagram-binary mode.

I CD40II QUAD 2 INPUT NAND GATE

92CS-1719\$R2

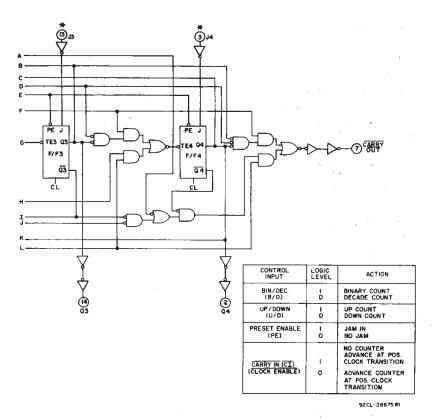
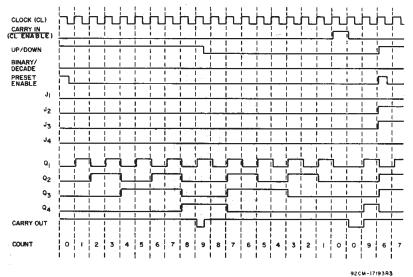


Fig. 9 - Logic diagram (cont'd).

Fig. 11 — Conversion of clock up, clock down input signals to clock and up/down input signals.

The CD4029B CLOCK and UP/DOWN inputs are used directly in most applications. In applications where CLOCK UP and CLOCK DOWN inputs are provided, conversion to the CD4029B CLOCK and UP/DOWN inputs can easily be realized by use of the circuit in Fig. 11.

CD4029B changes count on positive transitions of CLOCK UP or CLOCK DOWN inputs. For the gate configuration shown below, when counting up the CLOCK DOWN input must be maintained high and conversely when counting down the CLOCK UP input must be maintained high.



CD4029B Types

Fig. 12 - Timing diagram-decade mode.

DYNAMIC ELECTRICAL CHARACTERISTICS at T_A = 25°C, input t_f, t_f = 20 ns, C_ = 50 pF, R_ = 200 k Ω

CHARACTERISTIC	TEST CO	NDITIONS	ı	UNITS		
		V _{DD} (V)	Min.	Тур.	Max.	
Clocked Operation	.,					
Propagation Delay Time: tpHL, tpLH		5	_	250	500	
Q Output		10	_	120	240	
		15	_	90	180	
		5	_	280	560	
Carry Output		10	-	130	260	
	1	15	_	95	190	ns
		5	-	100	200	'''
Transition Time: t _{THL} , t _{TLH}		10		50	100	
Q Outputs, Carry Output		15	_	40	80	
		5	-	90	180	
Minimum Clock Pulse Width, tw		10	_	45	90	
		15	-	30	60	
		5	_	_	15	
Clock Rise & Fall Time, t _F CL, t _f CL**		10	_	-	15	μs
· '		15		_	15	'
*		5	_	170	340	
Minimum Setup Times, ts		10	_	70	140	ns
8/D or U/D		15	_	50	100	ĺ
		5	2	4	_	
Maximum Clock Input Frequency, fCL		10	4	8	_	MHz
		15	5.5	11	-	
Input Capacitance, C _{IN}	Any Input	t	-	5	7.5	ρF
Preset Enable						
		5		235	470	
Propagation Delay Time: tpHL, tpLH	Ì	10	_	100	200	
Q Outputs	Ì	15	_	80	160	
		5		320	640	
Carry Output	İ	10		145	290	
	1	15	-	105	210	ns
	1	5		65	130	112
Minimum Preset Enable Pulse Width, tw	ŀ	10		35	70	
*	Ì	15		25	50	
Military B. 11. 5	Ì	5	_	100	200	
Minimum Preset Enable Removal Time, tron *	1	10	_	55	110	
rime, trem*	Ì	15	-	40	80	
Carry Input						
Propagation Delay Time: tpHL, tpLH		5	_	170	340	
Carry Output		10	_	70	140	ns
		15		50	100	
Min. HOLD Time	Ī	5	-	25	50	ns
tµ*** Carry In	1	10		15	30	
	1	15	_	12	25	•
Min Set-Up Time		5	_	100	200	ns
t _s *** Carry in	İ	10	_	35	70	
a	ł	15		30	60	

^{*} From Up/Down, Binary/Decode, Carry In, or Preset Enable Control Inputs to Clock Edge.

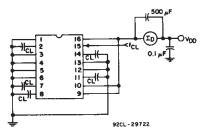


Fig. 13 - Power dissipation test circuit.

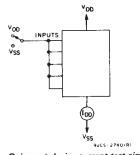


Fig. 14 - Quiescent-device current test circuit.

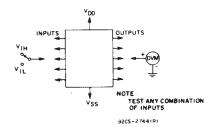


Fig. 15 - Input voltage test circuit.

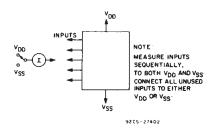
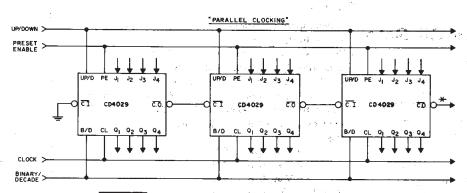


Fig. 16 - Input current test circuit.

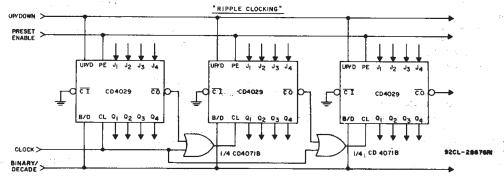
^{****}From Up/Lown, Binary/Jecode, Carry In, or Preset Enable Control injuris to Glock Edge.

***If more than one unit is cascaded in the parallel clocked application, t_vCL should be made less than or equal to the sum of the fixed propagation delay at 15 pF and the transition time of the carry output driving stage for the estimated capacitive load. This measurement was made with a decoupling capacitor (>1 µF) between V_{DD} and V_{SS}.

***From Carry In to Clock Edge



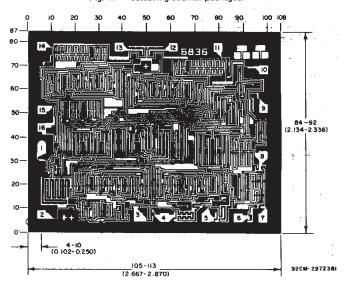
* CARRY OUT lines at the 2nd, 3rd, etc., stages may have a negative-going glitch pulse resulting from differential delays of different CD40298 fC's. These negative-going glitches do not affect proper CD40298 operation. However, if the CARRY OUT signals are used to trigger other edge-sensitive logic devices, such as FF's or counters, the CARRY OUT signals should be gated with the clock signal using a 2-input OR gate such as CD40718.



Ripple Clocking Mode:

The Up/Down control can be changed at any count. The only restriction on changing the Up/Down control is that the clock input to the first counting stage must be high. For cascading counters operating in a fixed up-count or down-count mode, the OR gates are not required between stages, and \overline{CO} is connected directly to the CL input of the next stage with \overline{CI} grounded.

Fig. 17 - Cascading counter packages.



Chip dimensions and pad layout for CD4029B

Dimensions in parentheses are in millimeters and are derived from the basic inch dimensions as indicated. Grid graduations are in mils (10^{-3} inch).





ti.com 28-Feb-2005

PACKAGING INFORMATION

Orderable Device	Status ⁽¹⁾	Package Type	Package Drawing	Pins	Package Qty	Eco Plan ⁽²⁾	Lead/Ball Finish	MSL Peak Temp ⁽³⁾
8101602EA	ACTIVE	CDIP	J	16	1	None	Call TI	Level-NC-NC-NC
CD4029BE	ACTIVE	PDIP	N	16	25	Pb-Free (RoHS)	CU NIPDAU	Level-NC-NC-NC
CD4029BF	ACTIVE	CDIP	J	16	1	None	Call TI	Level-NC-NC-NC
CD4029BF3A	ACTIVE	CDIP	J	16	1	None	Call TI	Level-NC-NC-NC
CD4029BM	ACTIVE	SOIC	D	16	40	Pb-Free (RoHS)	CU NIPDAU	Level-2-260C-1 YEAR/ Level-1-235C-UNLIM
CD4029BM96	ACTIVE	SOIC	D	16	2500	Pb-Free (RoHS)	CU NIPDAU	Level-2-260C-1 YEAR/ Level-1-235C-UNLIM
CD4029BMT	ACTIVE	SOIC	D	16	250	Pb-Free (RoHS)	CU NIPDAU	Level-2-260C-1 YEAR/ Level-1-235C-UNLIM
CD4029BNSR	ACTIVE	SO	NS	16	2000	Pb-Free (RoHS)	CU NIPDAU	Level-2-260C-1 YEAR/ Level-1-235C-UNLIM
CD4029BPW	ACTIVE	TSSOP	PW	16	90	Pb-Free (RoHS)	CU NIPDAU	Level-1-250C-UNLIM
CD4029BPWR	ACTIVE	TSSOP	PW	16	2000	Pb-Free (RoHS)	CU NIPDAU	Level-1-250C-UNLIM

⁽¹⁾ The marketing status values are defined as follows:

ACTIVE: Product device recommended for new designs.

LIFEBUY: TI has announced that the device will be discontinued, and a lifetime-buy period is in effect.

NRND: Not recommended for new designs. Device is in production to support existing customers, but TI does not recommend using this part in a new design.

PREVIEW: Device has been announced but is not in production. Samples may or may not be available.

OBSOLETE: TI has discontinued the production of the device.

(2) Eco Plan - May not be currently available - please check http://www.ti.com/productcontent for the latest availability information and additional product content details.

None: Not yet available Lead (Pb-Free).

Pb-Free (RoHS): TI's terms "Lead-Free" or "Pb-Free" mean semiconductor products that are compatible with the current RoHS requirements for all 6 substances, including the requirement that lead not exceed 0.1% by weight in homogeneous materials. Where designed to be soldered at high temperatures, TI Pb-Free products are suitable for use in specified lead-free processes.

Green (RoHS & no Sb/Br): TI defines "Green" to mean "Pb-Free" and in addition, uses package materials that do not contain halogens, including bromine (Br) or antimony (Sb) above 0.1% of total product weight.

(3) MSL, Peak Temp. -- The Moisture Sensitivity Level rating according to the JEDECindustry standard classifications, and peak solder temperature.

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14 LEADS SHOWN



- A. All linear dimensions are in inches (millimeters).
- B. This drawing is subject to change without notice.
- C. This package is hermetically sealed with a ceramic lid using glass frit.
- D. Index point is provided on cap for terminal identification only on press ceramic glass frit seal only.
- E. Falls within MIL STD 1835 GDIP1-T14, GDIP1-T16, GDIP1-T18 and GDIP1-T20.

N (R-PDIP-T**)

PLASTIC DUAL-IN-LINE PACKAGE

16 PINS SHOWN



- A. All linear dimensions are in inches (millimeters).
- B. This drawing is subject to change without notice.
- Falls within JEDEC MS-001, except 18 and 20 pin minimum body length (Dim A).
- The 20 pin end lead shoulder width is a vendor option, either half or full width.



D (R-PDSO-G16)

PLASTIC SMALL-OUTLINE PACKAGE



- A. All linear dimensions are in inches (millimeters).
- B. This drawing is subject to change without notice.
- C. Body dimensions do not include mold flash or protrusion not to exceed 0.006 (0,15).
- D. Falls within JEDEC MS-012 variation AC.



MECHANICAL DATA

NS (R-PDSO-G**)

14-PINS SHOWN

PLASTIC SMALL-OUTLINE PACKAGE



- A. All linear dimensions are in millimeters.
- B. This drawing is subject to change without notice.
- C. Body dimensions do not include mold flash or protrusion, not to exceed 0,15.



PW (R-PDSO-G**)

14 PINS SHOWN

PLASTIC SMALL-OUTLINE PACKAGE



NOTES: A. All linear dimensions are in millimeters.

B. This drawing is subject to change without notice.

C. Body dimensions do not include mold flash or protrusion not to exceed 0,15.

D. Falls within JEDEC MO-153

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Logic	logic.ti.com	Military	www.ti.com/military
Power Mgmt	power.ti.com	Optical Networking	www.ti.com/opticalnetwork
Microcontrollers	microcontroller.ti.com	Security	www.ti.com/security
		Telephony	www.ti.com/telephony
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